## Applicant(s)/Patent Under Application/Control No. Reexamination 10/765,276 TAKEOKA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 2825 Vuthe Siek **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 714/741 09-2002 Kapur et al. US-6,453,437 Α 702/185 \* 03-2004 US-6,708,139 Rearick et al. В US-С US-D Ε US-US-F US-G US-Н US-1 US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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